Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/768,090	YOSHIDA ET AL.
Examiner	Art Unit
Thinh T Nauven	2818

	SEAR	CHED	
Class	Subclass	Date	Examiner
438	285	4/4/2005 ·	TTN
438	240	4/4/2005	TTN
438	287	4/4/2005	TTN
438	180	4/4/2005	TTN
438	190	4/5/2005	TTN
438	197	4/5/2005	TTN
438	263	4/5/2005	TTN
438	310	4/5/2005	TTN

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
438	285	4/5/2005	TTN
438	240	4/5/2005	TTN

	DATE	EXMR
EAST	4/4/2005	TTN
	4/4/2003	1111
EAST	4/5/2005	TTN
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